

## **Electronic supplementary information**

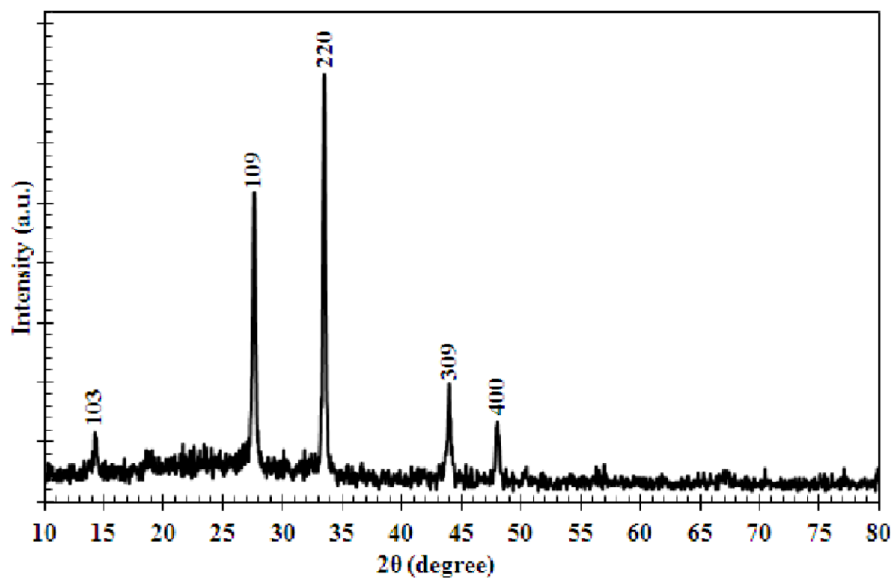
### **Magnetron sputtered Cu doped SnS thin films for improved photoelectrochemical and heterojunction solar cells**

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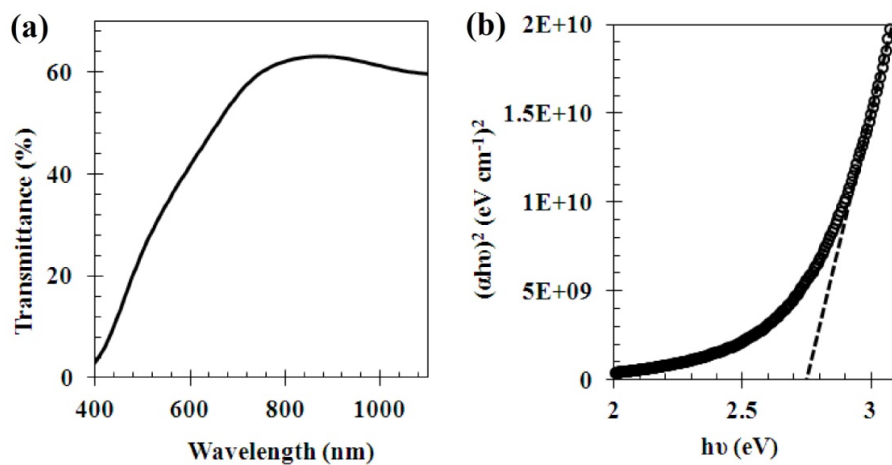
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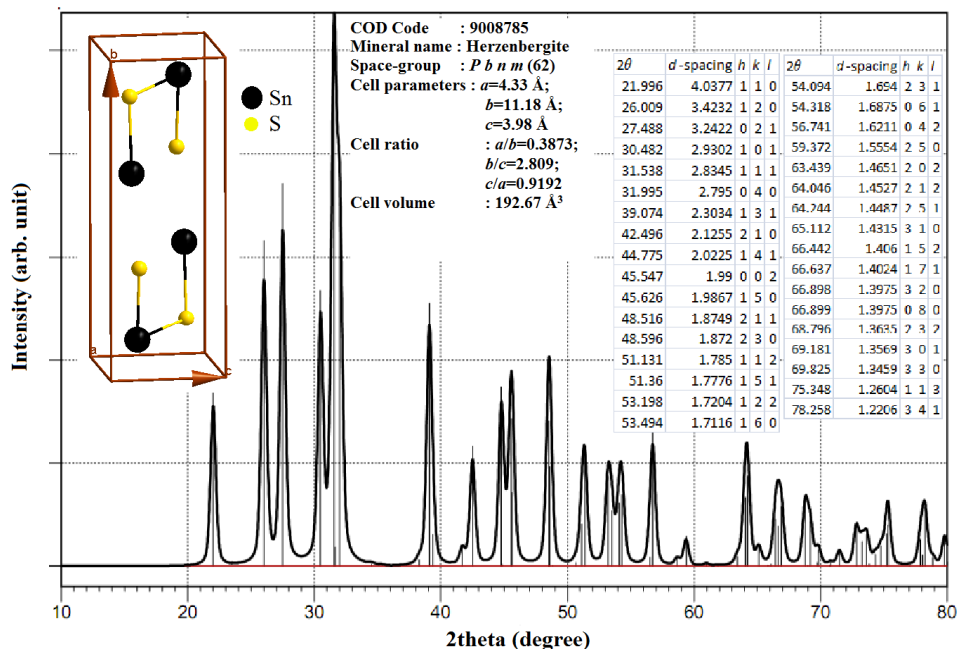
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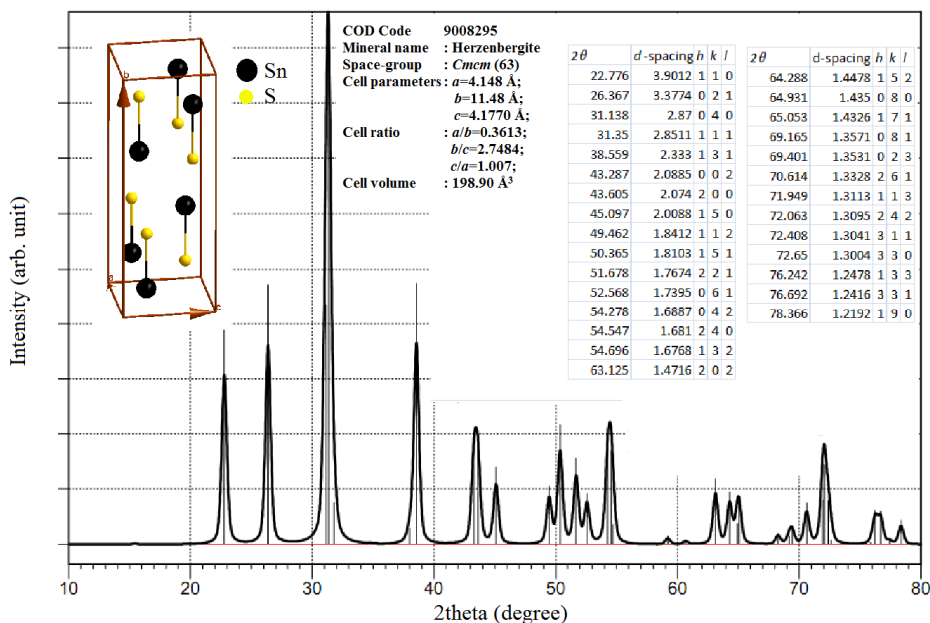
**Fig. S1:** The XRD spectra of  $\text{In}_2\text{S}_3$  revealed a tetragonal unit cell crystallized in I41 symmetry (JCPDS: 73-1366). The estimated lattice constants are  $a=4.63 \text{ \AA}$ ,  $b=4.63 \text{ \AA}$ ,  $c=32.07 \text{ \AA}$  with the crystallite size of 37 nm.



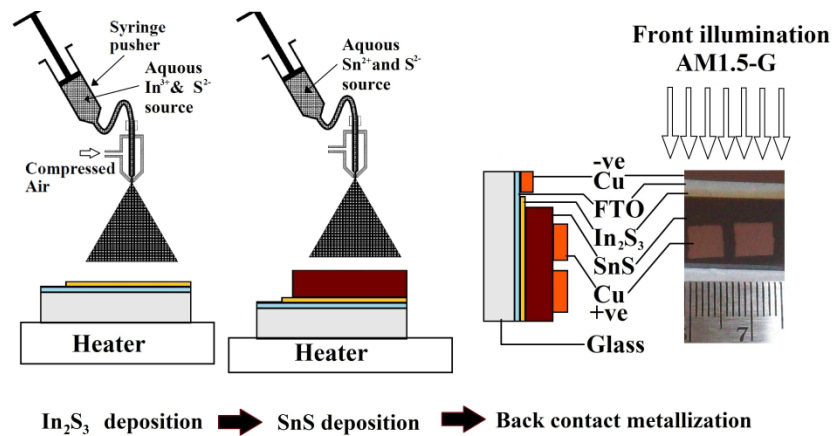
**Fig. S2:** Optical characterization of sprayed  $\text{In}_2\text{S}_3$  thin film on glass substrate (a) transmittance and (b) TauC plot. The direct optical band gap of 2.75 eV was estimated from TauC plot.



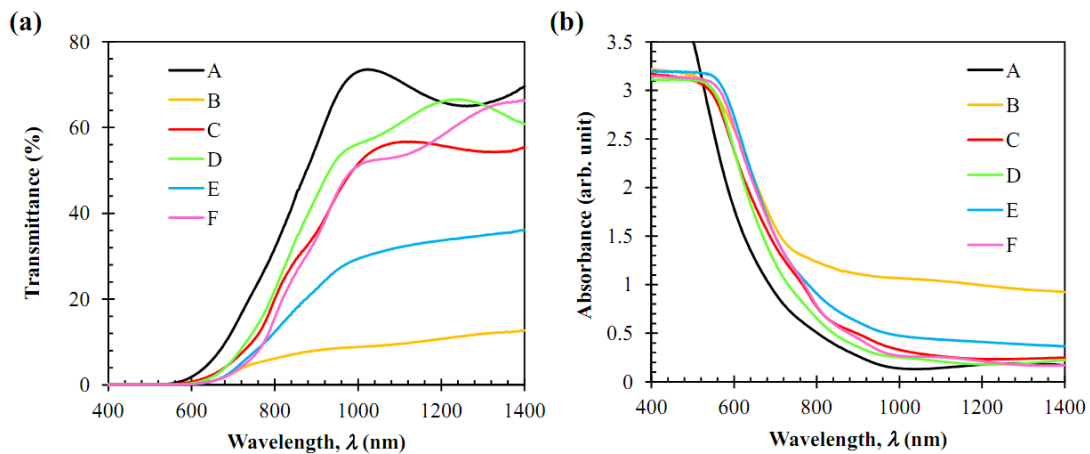
**Fig. S3:** XRD spectra of SnS material. It is generated by Pseudo-Voigt function for the SnS crystal structure of COD code 96-900-8285. The unit cell, lattice parameters and table of reflection are shown as insets.



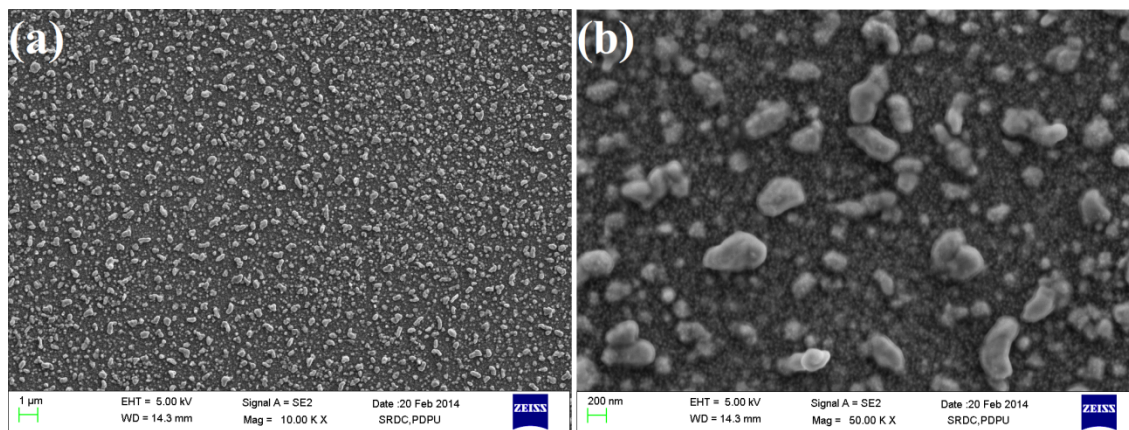
**Fig. S4:** XRD spectra of SnS material. It is generated by Pseudo-Voigt function for the SnS crystal structure of COD code 96-900-8295. The unit cell, lattice parameters and table of reflection are shown as insets.



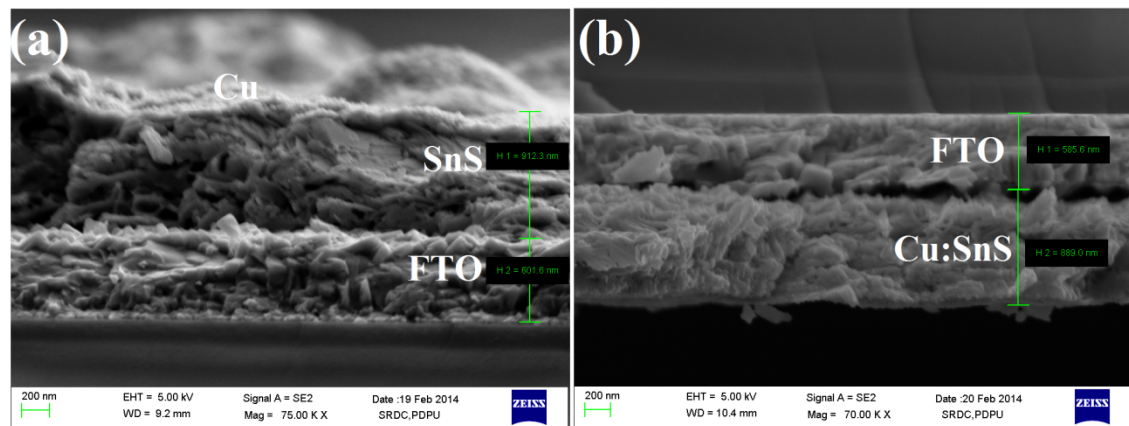
**Fig. S5:** Device fabrication scheme. The Superstrate configured SnS thin film solar cell was fabricated by inline approach. The Cu back contact was deposited at room temperature by thermal evaporation.



**Fig. S6:** Optical characterization of as sprayed and Cu doped SnS thin film on glass substrate (a) transmittance and (b) absorbance spectra.



**Fig. S7:** The field enhanced scanning electron micrograph of Cu deposited on glass substrate by pulsed DC magnetron sputtering, at a magnification of (a) 10 kX and (b) 50 kX.



**Fig. S8:** The field enhanced scanning electron micrograph of cross section of as Cu deposited on the SnS layer on the FTO coated glass substrate (a) before and (b) after Cu diffusion.